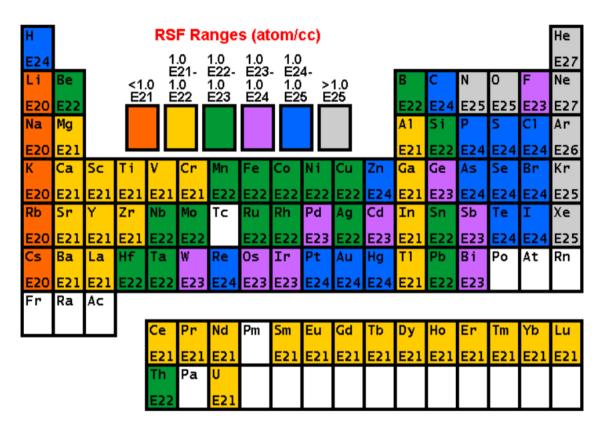
The tables below list Relative Sensitivity Factors (RSFs) based on data from R.G. Wilson (Int. J. Mass Spectrometry and Ion Processes, 143, 43, 1995). RSFs indicate how the sensitivity of detection varies depending on the element of interest.

- Lower RSF values correspond to higher sensitivity (meaning that ions can be detected even at low concentration).
- Even modest concentrations of elements with high sensitivity can saturate electron multiplier ion detectors so these can not be measured.

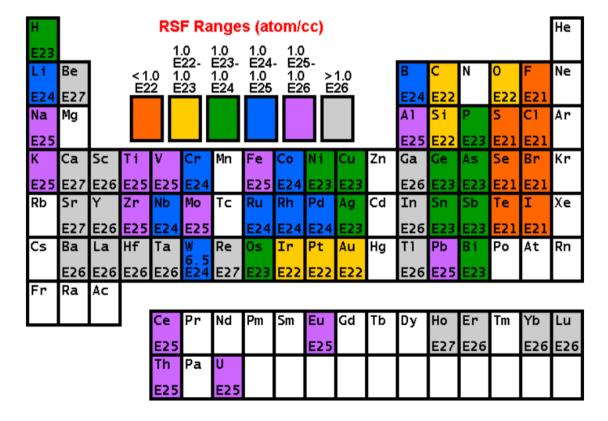
## O<sup>-</sup> primary beam

The following RSFs have been measured for oxygen primary ion bombardment, positive secondary ions, and a silicon matrix.



## Cs<sup>+</sup> primary beam

These RSFs have been measured for cesium primary ion bombardment, negative secondary ions, and a silicon matrix.



(R. G. Wilson Int. J. Mass Spectrometry. Ion Proc., 1995, 143, 43-49)